

Notice of References Cited	Application/Control No. 10/748,254		Applicant(s)/Patent Under Reexamination ABE, KAZUHIDE	
	Examiner W. David Coleman		Art Unit 2823	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	Antoni Bukaluk "AES studies of interdiffusion in thin-film copper-palladium multilayer structures", July 1999, Elvisier Science, Vaccum, vol. 54, pp. 279-283.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.